NI Educational Laboratory Virtual Instrumentation Suite (NI ELVIS)

User Manual



Worldwide Technical Support and Product Information

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All Class A products display a simple warning statement of one paragraph in length regarding interference and undesired operation. The FCC rules have restrictions regarding the locations where FCC Class A products can be operated. Consult the FCC Web site at www.fcc.gov for more information.

FCC/DOC Warnings

This equipment generates and uses radio frequency energy and, if not installed and used in strict accordance with the instructions in this manual and the CE marking Declaration of Conformity*, may cause interference to radio and television reception. Classification requirements are the same for the Federal Communications Commission (FCC) and the Canadian Department of Communications (DOC).

Changes or modifications not expressly approved by NI could void the user's authority to operate the equipment under the FCC Rules

Class A

Federal Communications Commission

This equipment has been tested and found to comply with the limits for a Class A digital device, pursuant to part 15 of the FCC Rules. These limits are designed to provide reasonable protection against harmful interference when the equipment is operated in a commercial environment. This equipment generates, uses, and can radiate radio frequency energy and, if not installed and used in accordance with the instruction manual, may cause harmful interference to radio communications. Operation of this equipment in a residential area is likely to cause harmful interference in which case the user is required to correct the interference at their own expense.

Canadian Department of Communications

This Class A digital apparatus meets all requirements of the Canadian Interference-Causing Equipment Regulations. Cet appareil numérique de la classe A respecte toutes les exigences du Règlement sur le matériel brouilleur du Canada.

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Readers in the European Union (EU) must refer to the manufacturer's Declaration of Conformity (DoC) for information* pertaining to the CE marking compliance scheme. The manufacturer includes a DoC for most hardware products except for those bought from OEMs. In addition, DoCs are usually not provided if compliance is not required, for example electrically benign apparatus or cables.

To obtain the DoC for this product, click **Declaration of Conformity** at ni.com/hardref.nsf/. This Web site lists the DoCs by product family. Select the appropriate product family, followed by your product, and a link to the DoC appears in Adobe Acrobat format. Click the Acrobat icon to download or read the DoC.

* The CE marking Declaration of Conformity contains important supplementary information and instructions for the user or installer.

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About This Manual

Thank you for purchasing the National Instruments Educational Laboratory Virtual Instrumentation Suite (NI ELVIS). The *NI ELVIS User Manual* contains information that you need to understand and program the NI ELVIS architecture and instruments. The *NI ELVIS User Manual* also discusses the components of an NI data acquisition (DAQ) system and the concept of virtual instrumentation.

Conventions

<>

The following conventions appear in this manual:

Angle brackets that contain numbers separated by an ellipsis represent a

range of values associated with a bit or signal name—for example,

DIO<3..0>.

The » symbol leads you through nested menu items and dialog box options to a final action. The sequence **File»Page Setup»Options** directs you to

pull down the File menu, select the Page Setup item, and select Options

from the last dialog box.

This icon denotes a note, which alerts you to important information.

This icon denotes a caution, which advises you of precautions to take to avoid injury, data loss, or a system crash. When this symbol is marked on the product, refer to the *Safety Information* section of Chapter 1, *DAQ*

System Overview, for precautions to take.

bold Bold text denotes items that you must select or click in the software, such

as menu items and dialog box options. Bold text also denotes parameter

names and hardware labels.

DAQ device DAQ device refers to any National Instrument DAQ device that meets the

conditions listed in the DAQ Hardware section of Chapter 3, Hardware

Overview.

ELVIS Educational Laboratory Virtual Instrumentation Suite

italic Italic text denotes variables, emphasis, a cross reference, or an introduction

to a key concept. This font also denotes text that is a placeholder for a word

or value that you must supply.

monospace

Text in this font denotes text or characters that you should enter from the keyboard, sections of code, programming examples, and syntax examples. This font is also used for the proper names of disk drives, paths, directories, programs, subprograms, subroutines, device names, functions, operations, variables, filenames and extensions, and code excerpts.

PCI

Peripheral Component Interconnect—a high-performance expansion bus architecture originally developed by Intel to replace ISA and EISA

Related Documentation

The following documents contain information that you might find helpful as you read this manual:

- DAQ device user manual, available at ni.com/manuals
- Getting Started with LabVIEW, available at ni.com/manuals
- LabVIEW Help, available by selecting Help»VI, Function, and How-To Help from the LabVIEW block diagram or front panel
- LabVIEW Measurements Manual, available at ni.com/manuals
- Measurement & Automation Explorer Help for DAQ, available by selecting Help»Help Topics»NI-DAQ from the Measurement & Automation Explorer (MAX) window
- Where to Start with NI ELVIS, available in PDF format on the NI ELVIS Software CD
- NI ELVIS Online Help, available on the NI ELVIS Software CD or from ni.com/manuals

DAQ System Overview

This chapter briefly describes the concept of DAQ systems and introduces NI ELVIS, a DAQ system designed for educational laboratories.

What is DAQ?

DAQ systems capture, measure, and analyze physical phenomena from the real world. Light, temperature, pressure, and torque are examples of the different types of signals that a DAQ system can measure. Data acquisition is the process of collecting and measuring electrical signals from transducers and test probes or fixtures, and sending them to a computer for processing. Data acquisition may also include the output of analog or digital control signals.

The building blocks of a DAQ system include the following items:

- Transducer—A device that converts a physical phenomenon such as light, temperature, pressure, or sound into a measurable electrical signal such as voltage or current.
- Signal—The product of the DAQ system transducer.
- Signal conditioning—Hardware that you can connect to the DAQ device to make the signal suitable for measurement or to improve accuracy or reduce noise. The most common types of signal conditioning include amplification, excitation, linearization, isolation, and filtering.
- DAQ hardware—Hardware you use to acquire, measure, and analyze data.
- Software—NI application software is designed to help you easily design and program your measurement and control application.

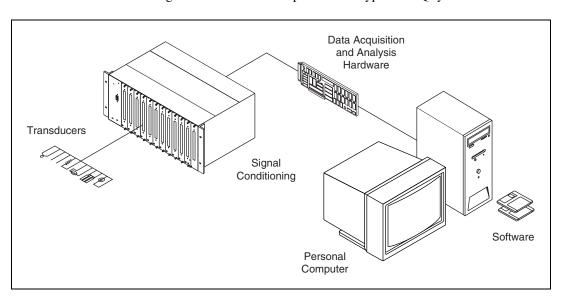


Figure 1-1 shows the components of a typical DAQ system.

Figure 1-1. Typical DAQ System

The NI ELVIS incorporates DAQ hardware and software, the last two of the DAQ system components, into one product. The following sections give more information about DAQ hardware and software, which is LabVIEW in the case of NI ELVIS.

DAQ Hardware

Since DAQ devices acquire electrical signals, a transducer or a sensor must convert some physical phenomenon into an electrical signal. A DAQ system can also simultaneously produce electrical signals. These signals can either intelligently control mechanical systems or provide a stimulus so that the DAQ system can measure a response. Most DAQ devices have four standard elements: analog input (AI), analog output (AO), digital I/O (DIO), and counter/timers. The most common National Instruments DAQ devices are the E Series devices.

The *DAQ Hardware* section of Chapter 3, *Hardware Overview*, describes in greater detail the DAQ device used as part of the NI ELVIS. Refer to the DAQ device user manual, at ni.com/manuals for specific information about the functionality and operation of the device.

LabVIEW

LabVIEW is a graphical programming language frequently used for creating test, measurement, and automation applications. LabVIEW uses icons instead of lines of text to create applications. Unlike text-based programming languages, LabVIEW uses dataflow programming, where the flow of data determines execution. In LabVIEW, you build a user interface by using a set of tools and objects. The user interface is known as the *front panel*. You then add code using graphical representations of functions to control the front panel objects. The *block diagram* contains this code. In some ways, the block diagram resembles a flowchart. A *virtual instrument* (VI) is a LabVIEW program that models the appearance and function of a physical instrument.

The flexibility, modular nature, and ease-of-use programming possible with LabVIEW makes it popular in top university laboratories. With LabVIEW, you can rapidly create applications using intuitive graphical development and add user interfaces for interactive control. Scientists and engineers can use the straightforward I/O functionality of LabVIEW along with its analysis capabilities. LabVIEW can also be used in the classrooms to solve purely analytical or numerical problems.

For more information on programming with LabVIEW, refer to *Getting Started with LabVIEW* and the *LabVIEW Measurements Manual*, available at ni.com/manuals. *LabVIEW Help* is available by selecting **Help»VI, Function, and How-To Help** from the LabVIEW block diagram or front panel, or you can select **Help»Search the LabVIEW Bookshelf** from the block diagram or front panel to display other relevant LabVIEW documentation.

Virtual Instrumentation

Virtual instrumentation is defined as the combination of measurement and control hardware and application software with industry-standard computer technology to create user-defined instrumentation systems.

Virtual instrumentation provides an ideal platform for developing instructional curriculum and conducting scientific research. In an instructional laboratory course, students perform various experiments that combine measurements, automation, and control. Tools or systems used in these situations must be flexible and adaptable. In research environments, virtual instrumentation provides the flexibility that a researcher must have to modify the system to meet unpredictable needs. Research and instructional efforts also require that their systems be economical. Since you can reuse components in a virtual instrumentation system (without

purchasing additional hardware or software), virtual instrumentation is an economical choice. Finally, measurement systems must be scalable to meet future expansion needs. The modular nature of virtual instrumentation makes it easy for you to add new functionality.

NI ELVIS Overview

NI ELVIS uses LabVIEW-based software instruments, a multifunction DAQ device, and a custom-designed benchtop workstation and prototyping board to provide the functionality of a suite of common laboratory instruments.

The LabVIEW software that you use to interact with the NI ELVIS Benchtop Workstation and the DAQ device provides a high-level programming environment for easy implementation of the sophisticated display and analysis capabilities required for virtual instrumentation.

The NI ELVIS hardware provides a Function Generator and Variable Power Supplies from the benchtop workstation. The NI ELVIS LabVIEW soft front panel instruments combined with the functionality of the DAQ device provide the functionality of the following SFP instruments:

- Arbitrary Waveform Generator (ARB)
- Bode Analyzer
- Digital Bus Reader
- Digital Bus Writer
- Digital Multimeter (DMM)
- Dynamic Signal Analyzer (DSA)
- Function Generator (FGEN)
- Impedance Analyzer
- Oscilloscope (Scope)
- Two-Wire Current Voltage Analyzer
- Three-Wire Current Voltage Analyzer
- Variable Power Supplies

Refer to Figure 2-1, *The NI ELVIS System*, in Chapter 2, *NI ELVIS Overview*, for an illustration of the NI ELVIS.

Safety Information

The following section contains important safety information that you *must* follow when installing and using the product.

Do *not* operate the product in a manner not specified in this document. Misuse of the product can result in a hazard. You can compromise the safety protection built into the product if the product is damaged in any way. If the product is damaged, return it to National Instruments for repair.

Do *not* substitute parts or modify the product except as described in this document. Use the product only with the chassis, modules, accessories, and cables specified in the installation instructions. You *must* have all covers and filler panels installed during operation of the product.

Do *not* operate the product in an explosive atmosphere or where there may be flammable gases or fumes. If you must operate the product in such an environment, it must be in a suitably rated enclosure.

If you need to clean the product, use a soft, nonmetallic brush. Make sure that the product is completely dry and free from contaminants before returning it to service.

Operate the product only at or below Pollution Degree 1. Pollution is foreign matter in a solid, liquid, or gaseous state that can reduce dielectric strength or surface resistivity. The following is a description of pollution degrees:

- Pollution Degree 1 means no pollution or only dry, nonconductive pollution occurs. The pollution has no influence.
- Pollution Degree 2 means that only nonconductive pollution occurs in most cases. Occasionally, however, a temporary conductivity caused by condensation must be expected.
- Pollution Degree 3 means that conductive pollution occurs, or dry, nonconductive pollution occurs that becomes conductive due to condensation.

You *must* insulate signal connections for the maximum voltage for which the product is rated. Do *not* exceed the maximum ratings for the product. Do not install wiring while the product is live with electrical signals. Do not remove or add connector blocks when power is connected to the system. Avoid contact between your body and the connector block signal when hot swapping modules. Remove power from signal lines before connecting them to or disconnecting them from the product.

Operate the product at or below the *installation category*¹ marked on the hardware label. Measurement circuits are subjected to *working voltages*² and transient stresses (overvoltage) from the circuit to which they are connected during measurement or test. Installation categories establish standard impulse withstand voltage levels that commonly occur in electrical distribution systems. The following is a description of installation categories:

- Installation Category I is for measurements performed on circuits not directly connected to the electrical distribution system referred to as MAINS³ voltage. This category is for measurements of voltages from specially protected secondary circuits. Such voltage measurements include signal levels, special equipment, limited-energy parts of equipment, circuits powered by regulated low-voltage sources, and electronics.
- Installation Category II is for measurements performed on circuits directly connected to the electrical distribution system. This category refers to local-level electrical distribution, such as that provided by a standard wall outlet (for example, 115 V for U.S. or 230 V for Europe). Examples of Installation Category II are measurements performed on household appliances, portable tools, and similar product.
- Installation Category III is for measurements performed in the building installation at the distribution level. This category refers to measurements on hard-wired equipment such as equipment in fixed installations, distribution boards, and circuit breakers. Other examples are wiring, including cables, bus-bars, junction boxes, switches, socket-outlets in the fixed installation, and stationary motors with permanent connections to fixed installations.
- Installation Category IV is for measurements performed at the primary electrical supply installation (<1,000V). Examples include electricity meters and measurements on primary overcurrent protection devices and on ripple control units.

¹ Installation categories, also referred to as *measurement categories*, are defined in electrical safety standard IEC 61010-1.

² Working voltage is the highest rms value of an AC or DC voltage that can occur across any particular insulation.

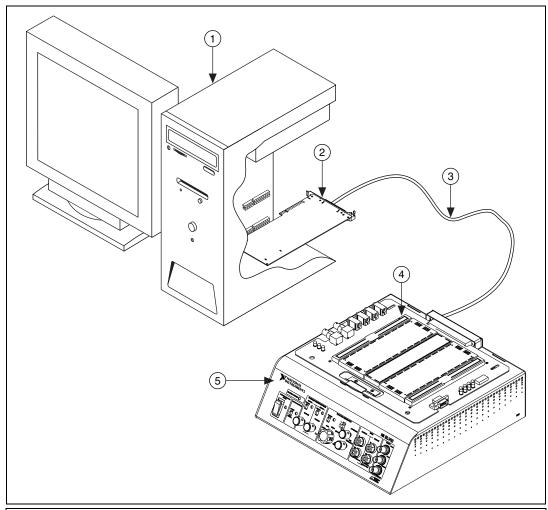
³ MAINS is defined as a hazardous live electrical supply system that powers equipment. Suitably rated measuring circuits may be connected to the MAINS for measuring purposes.

NI ELVIS Overview

NI ELVIS combines hardware and software into one complete laboratory suite. This chapter provides an overview of the hardware and software components of the NI ELVIS. Additionally, this chapter discusses how NI ELVIS can be used in various academic environments.

Chapter 3, *Hardware Overview*, provides more detailed information about NI ELVIS hardware components. Refer to the *NI ELVIS Online Help* for more information about the software components.

Refer to Figure 2-1 for a diagram of the NI ELVIS system.



- 1 Computer Running LabVIEW
- 2 DAQ Device
- 3 68-Pin E Series Cable

- 4 NI ELVIS Prototyping Board
- 5 NI ELVIS Benchtop Workstation

Figure 2-1. The NI ELVIS System

NI ELVIS Hardware

The following sections briefly describe the hardware components of the NI ELVIS. For more specific information about these components, refer to Chapter 3, *Hardware Overview*.

NI ELVIS Benchtop Workstation

The benchtop workstation and the DAQ device together create a complete laboratory system. The workstation provides connectivity and functionality. The control panel on the workstation provides easy-to-operate knobs for the function generator and variable power supplies, and it offers convenient connectivity in the form of BNC and banana-style connectors to the NI ELVIS - Scope SFP and NI ELVIS - DMM SFP. The NI ELVIS software routes signals in the NI ELVIS Benchtop Workstation between the SFP instruments. For example, the output of the function generator may be routed to a specific channel of the DAQ device and ultimately acquired on a desired channel of the NI ELVIS - Scope SFP. The benchtop workstation also contains a protection board that protects the DAQ device from possible damage resulting from laboratory errors.

Refer to the *NI ELVIS Benchtop Workstation* section of Chapter 3, *Hardware Overview*, for more detailed information about the benchtop workstation, including the parts locator diagram.

NI ELVIS Prototyping Board

The NI ELVIS Prototyping Board connects to the benchtop workstation. The prototyping board provides an area for building electronic circuitry and allows the connections necessary to access signals for common applications. You can use multiple prototyping boards interchangeably with the NI ELVIS Benchtop Workstation.

Refer to the *NI ELVIS Prototyping Board* section of Chapter 3, *Hardware Overview*, for more information about the prototyping board, including signal descriptions, connection instructions, and the parts locator diagram.

NI ELVIS Software

The NI ELVIS software, created in LabVIEW, takes advantage of the capabilities of virtual instrumentation. The software includes two main types: the soft front panel (SFP) instruments and the LabVIEW API for programming the NI ELVIS hardware.

SFP Instruments

NI ELVIS ships with the SFP instruments, created in LabVIEW, and the source code for the instruments. You cannot directly modify the executable files, but you can modify or enhance the functionality of these instruments

by modifying the LabVIEW code. The instruments are virtual instruments (VIs) that are necessary in typical laboratory applications.

This section briefly describes each SFP instrument included with NI ELVIS. The instrument software is LabVIEW-based, so you can customize the instruments by modifying the LabVIEW code.

Instrument Launcher

The NI ELVIS Instrument Launcher provides access to the NI ELVIS software instruments. To launch an instrument, click the button corresponding to the desired instrument. If the NI ELVIS software is properly configured and the benchtop workstation is cabled to the appropriate DAQ device, all buttons should be visible.

If there is a problem with your configuration, such as when the NI ELVIS Benchtop Workstation is powered off or disconnected from the configured DAQ device, all instrument buttons are dimmed, and the only available option is to click the **Configure** button. Refer to *Where to Start with the NI ELVIS* for more information about configuring NI ELVIS.

Some instruments perform similar operations using the same resources of the NI ELVIS hardware and the DAQ device and cannot be run at the same time. If you launch two instruments with overlapping functionality that cannot run at the same time, the NI ELVIS software generates an error dialog describing the conflict. The instrument with the error is disabled and will not function until the conflict is resolved.

Arbitrary Waveform Generator (ARB)

This advanced-level SFP instrument uses the AO capabilities of the DAQ device. You can create a variety of signal types using the Waveform Editor software, which is included with the NI ELVIS software. You can load waveforms created with the NI Waveform Editor into the ARB SFP to generate stored waveforms. Refer to the *NI ELVIS Online Help* for more information about the Waveform Editor.

Since a typical DAQ device has two AO channels, two waveforms may be simultaneously generated. You can choose continuous output or a one-shot output. The minimum output rate of the NI ELVIS - ARB SFP is determined by the maximum update rate of the DAQ device connected to the NI ELVIS hardware. Refer to the DAQ device user manual for these specifications.

Bode Analyzer

By combining the frequency sweep feature of the function generator and the AI capability of the DAQ device, a full-function Bode Analyzer is available with NI ELVIS. You can set the frequency range of the instrument and choose between linear and dB display scales.

Digital Bus Reader

This instrument reads digital data from the NI ELVIS digital input (DI) bus. You can either continuously read from the bus, or you can take a single reading.

Digital Bus Writer

This instrument updates the NI ELVIS digital output (DO) bus with user-specified digital patterns. You can manually create a pattern or select predefined patterns, such as ramp, toggle, or walking ones. This instrument can either continually output a pattern or just perform a single write. The output of the NI ELVIS - Digital Bus Writer SFP stays latched until the instrument is stopped or another pattern is output. Output voltage levels of the SFP are TTL compatible.

Digital Multimeter (DMM)

This commonly used instrument can perform the following types of measurements:

- DC voltage
- AC voltage
- Current (DC and AC)
- Resistance
- Capacitance
- Inductance
- Diode test
- Audible continuity

You can connect to the DMM from the NI ELVIS Prototyping Board or from the banana-style connectors on the front panel of the benchtop workstation.

Dynamic Signal Analyzer (DSA)

This instrument is especially useful in advanced electrical engineering and physics classes. This instrument uses the analog input of the DAQ device to make measurements and can either continuously make measurements or make a single scan. You can also apply various window and filtering options to the signal.

Function Generator (FGEN)

This instrument provides you with choices for the type of output waveform (sine, square, or triangle), amplitude selection, and frequency settings. In addition, the instrument offers DC offset setting, frequency sweep capabilities, and modulation.

Impedance Analyzer

This instrument is a basic impedance analyzer that is capable of measuring the resistance and reactance for passive two-wire elements at a given frequency.

Oscilloscope (Scope)

This instrument provides the functionality of the standard desktop instrument found in typical undergraduate laboratories. The NI ELVIS - Scope SFP has two channels and provides scaling and position adjustment knobs along with a modifiable timebase. You also can choose trigger source and mode settings. Depending on the DAQ device cabled to the NI ELVIS hardware, you can choose between digital or analog hardware triggering. You can connect to the NI ELVIS - Scope SFP from the NI ELVIS Prototyping Board or from the BNC connectors on the front panel of the benchtop workstation.

The FGEN or DMM signals can be routed to this instrument. In addition, this computer-based scope display has the ability to use cursors for accurate screen measurements. The sampling rate of the Oscilloscope is determined by the maximum sampling speed of the DAQ device installed in the computer attached to the NI ELVIS hardware.

Refer to the DAQ device user manual for information about the type of triggering supported on the device and for the specifications for the maximum sampling speed of the device.

Two-Wire and Three-Wire Current-Voltage Analyzers

These instruments allow you to conduct diode and transistor parametric testing and view current-voltage curves. The two-wire instrument offers full flexibility in setting parameters such as voltage and current ranges and can save data to a file. In addition, the three-wire instrument offers base current settings for measurements of NPN transistors. Both instruments have cursors for more accurate onscreen measurements.

Variable Power Supplies

You can control the output of the positive or negative variable power supply with these SFP instruments. The negative power supply can output between -12 and 0 V, and the positive power supply can output between 0 and +12 V.



Note For a detailed explanation of the soft front panel instruments and instructions for taking a measurement with each instrument, refer to the *NI ELVIS Online Help*.

NI ELVIS LabVIEW API

The NI ELVIS software also includes APIs to program four features of the NI ELVIS hardware: the DIO, DMM, FGEN, and Variable Power Supplies. Refer to Chapter 4, *Programming NI ELVIS*, for more information about using the APIs to program NI ELVIS.



Note For the VI reference for each API, refer to the *NI ELVIS Online Help*.

NI ELVIS in Academic Disciplines

You can use NI ELVIS in engineering, physical sciences, and biological sciences laboratories. NI ELVIS is suitable not only in terms of the included software, but also because of the custom signal conditioning hardware you can create with NI ELVIS. Instructors can implement the NI ELVIS curriculum with beginning to advanced classes to provide hands-on experience to students.

NI ELVIS in Engineering

NI ELVIS is suited for teaching basic electronics and circuit design to students in electrical engineering, mechanical engineering, and biomedical engineering. The suite offers full testing, measurement, and data-saving capabilities needed for such training. Students can use the removable prototyping board at home to build circuits, thus using laboratory time more effectively.

NI ELVIS SFP instruments, such as the Bode Analyzer, offer instructors an opportunity to teach advanced courses in signal analysis and processing. Students may construct software filters in LabVIEW and hardware filters on the prototyping board and compare the performance of those two types of filters.

Mechanical engineering students can learn sensor and transducer measurements in addition to basic circuit design by building custom signal conditioning. Students can install custom sensor adapters on the prototyping board. For example, installing a thermocouple jack on the prototyping board allows robust thermocouple connections. The programmable power supply can provide excitation for strain gauges used in strain measurements.

NI ELVIS in Biological Sciences

Biomedical engineering departments have challenges that are similar to those of mechanical departments. Students typically learn basic electronics and build instruments such as an electrocardiogram (ECG) monitor. The prototyping board offers signal conditioning capability for ECG sensors, and the NI ELVIS SFP instruments are ideal for testing the circuits as students build the signal conditioning circuits.

NI ELVIS in Physical Sciences

Physics students typically learn electronics and circuit design theory. NI ELVIS provides these students with the opportunity to implement these concepts. Physics students sometimes need signal conditioning for common sensors such as photoelectric multiplier or light detector sensors. Students can build high-gain, low-noise circuits on a printed circuit board (PCB) and use them in modern physics labs.



Caution The NI ELVIS hardware is *not* environmentally sealed; therefore, exercise extreme caution for use in chemical and biological sciences.

Hardware Overview

This chapter describes the hardware components of the NI ELVIS, including the DAQ device, the benchtop workstation, and the prototyping board.

DAQ Hardware

NI ELVIS is designed to interact with National Instruments DAQ devices, which are high-performance, multifunction analog, digital, and timing I/O devices for PCI bus computers. Supported functions on DAQ devices include AI, AO, DIO, and timing I/O (TIO).

To use the NI ELVIS, the DAQ device installed in the computer connected to the NI ELVIS must have the following minimum requirements:

- 16 AI channels
- Two AO channels
- · Eight DIO lines
- Two counter/timers



Note The NI ELVIS does not support 64 AI channel DAQ devices or DIO-only devices.

Using the DAQ Hardware in Bypass Mode

The NI ELVIS communicates with the computer through the eight DIO lines of the DAQ device. The **Communications** switch controls the routing of the DIO to the NI ELVIS. In normal operation, the switch is in Normal mode, and the DIO lines are routed to the NI ELVIS hardware, allowing software control. When the **Communications** switch is set to Bypass mode, the LED next to the switch is lit. No communication changes occur unless you use the NI ELVIS - Enable Communications Bypass VI in conjunction with putting the switch in Bypass mode. After you move the switch and run the VI, the DIO lines are routed to the DI lines on the prototyping board. Figure 3-1 shows the location of the **Communications** switch.

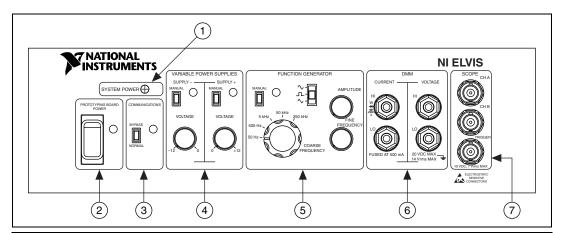
When in Bypass mode, the hardware Function Generator and Variable Power Supplies are still available through the manual controls. The counter/timers, AI, and AO on the DAQ device are also available. The NI ELVIS SFP instruments notify you when the **Communications** switch is in Bypass mode. Some SFP controls are dimmed when the **Communications** switch is moved to Bypass mode.

For detailed information about the DAQ device, refer to the device user manual, which you can download at ni.com/manuals.

NI ELVIS Benchtop Workstation

This section describes the NI ELVIS Benchtop Workstation and the control panel on the front of the workstation.

Refer to Figure 3-1 for the parts locator diagram for the benchtop workstation.



- 1 System Power LED
- 2 Prototyping Board Power Switch
- 3 Communications Switch
- 4 Variable Power Supplies Controls

- 5 Function Generator (FGEN) Controls
- 6 DMM Connectors
- 7 Oscilloscope (Scope) Connectors

Figure 3-1. Control Panel Diagram of the Benchtop Workstation

The benchtop workstation has the following controls and indicators:

- **System Power LED**—Indicates whether the NI ELVIS is powered on.
- **Prototyping Board Power Switch**—Controls the power to the prototyping board.

- Communications Switch—Requests disabling software control of the NI ELVIS. This setting provides direct access to the DAQ device DIO lines. For more information about the Communications switch, refer to the Using the DAQ Hardware in Bypass Mode section.
- Variable Power Supplies Controls



Note You can control the variable power supplies through either the hardware controls on the benchtop workstation (Manual mode) or the controls on the NI ELVIS - Variable Power Supplies SFP (Software mode). You can only use the controls described in the following section when the variable power supplies are in Manual mode.

- Supply- Controls
 - Manual Switch—Controls whether the negative supply is in Manual mode or Software mode.
 - **Voltage Adjust Knob**—Controls the output of the negative supply. The negative supply can output between -12 and 0 V.
- Supply+ Controls
 - Manual Switch—Controls whether the positive supply is in Manual mode or Software mode.
 - **Voltage Adjust Knob**—Controls the output of the positive supply. The positive supply can output between 0 and +12 V.

For more information about the software controls for the Variable Power Supplies, refer to the *NI ELVIS Online Help*.

• Function Generator Controls



Note You can control the function generator through either the hardware controls on the benchtop workstation (Manual mode) or the controls on the NI ELVIS - FGEN SFP (Software mode). You can only use the controls described in the following section when the function generator is in Manual mode.

- Manual Switch—Controls whether the Function Generator is in Manual mode or Software mode.
- Function Selector—Selects what type of waveform is generated.
 NI ELVIS can generate sine, square, or triangle waves.
- Amplitude Knob—Adjusts the peak amplitude of the generated waveform.
- Coarse Frequency Knob—Sets the range of frequencies the Function Generator can output.

 Fine Frequency Knob—Adjusts the output frequency of the Function Generator.

For more information about the software controls for the function generator, refer to the *NI ELVIS Online Help*.

• DMM Connectors



Caution By connecting different signals to both the DMM terminals on the prototyping board and the DMM connectors on the control panel, you are shorting them together, potentially damaging the circuit on the prototyping board.

CURRENT Banana Jacks

- **HI**—The positive input to all the DMM functionality, except measuring voltage.
- **LO**—The negative input to all the DMM functionality, except measuring voltage.

VOLTAGE Banana Jacks

- **HI**—The positive input for voltage measurements.
- **LO**—The negative input for voltage measurements.

• Oscilloscope (Scope) Connectors



Caution By connecting different signals to the Scope terminals on the prototyping board and the Scope connectors on the control panel, you are shorting them together, potentially damaging the circuit on the prototyping board.

- CH A BNC Connector—The input for channel A of the Oscilloscope.
- CH B BNC Connector—The input for channel B of the Oscilloscope.
- Trigger BNC Connector—The input to the trigger of the Oscilloscope.

NI ELVIS Protection Board

NI ELVIS protects the DAQ device installed in the desktop computer by means of a protection board located inside the NI ELVIS Benchtop Workstation. This removable protection board provides short-circuit protection from unsafe external signals. Removing the protection board enables you to quickly replace a nonfunctioning board with a replacement unit. The components on the protection board are easily obtained from

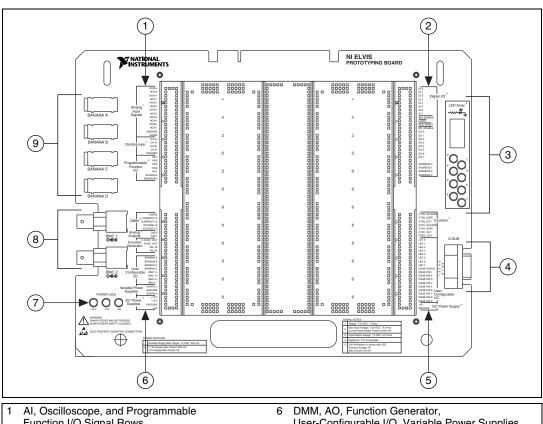
electronics vendors and thus can be serviced without sending the board to NI for repairs.

Refer to Appendix B, *Protection Board Fuses*, for more information about changing the fuses on the NI ELVIS Protection Board.

NI ELVIS Prototyping Board

This section describes the NI ELVIS Prototyping Board and how you can use it to connect circuits to the NI ELVIS. This section also describes the signals that you can connect to the NI ELVIS from the prototyping board and the connectors you can use to do so.

The prototyping board connects to the benchtop workstation with a standard PCI connector, so you can create custom PCBs to interact with NI ELVIS. The prototyping board exposes all the signal terminals of the NI ELVIS to the user through the distribution strips on either side of the breadboard area. Each signal has a row, and the rows are grouped by function.



Refer to Figure 3-2 for the parts locator diagram for the prototyping board.

- Function I/O Signal Rows
- **DIO Signal Rows**
- LED Array
- **D-Sub Connector**
- Counter/Timer, User-Configurable I/O, and DC Power Supply Signal Rows
- User-Configurable I/O, Variable Power Supplies, and DC Power Supplies Signal Rows
- Power LEDs
- **BNC Connectors**
- Banana Jack Connectors

Figure 3-2. Prototyping Board Parts Locator Diagram

Prototyping Board Power

The prototyping board provides access to a ± 15 V and a ± 5 V power supply. You can use these voltage rails to construct many common circuits. Refer to Appendix A, Specifications, for more information about these voltage rails.

Prototyping Board Signal Descriptions

Table 3-1 describes the signals on the NI ELVIS prototyping board. The signals are grouped by the functionality section where they are located on the prototyping board.

Table 3-1. Signal Descriptions

Signal Name	Туре	Description
ACH<05>+	General AI	Analog Input Channels 0 through 5 (+)—Positive differential input to the AI channels.
ACH<05>-	General AI	Analog Input Channels 0 through 5 (–)—Negative differential input to the AI channels.
AISENSE	General AI	Analog Input Sense—Reference for the analog channels in nonreferenced single-ended (NRSE) mode. For more information on AI modes, refer to the DAQ device user manual.
AIGND	General AI	Analog Input Ground—AI ground reference for the DAQ device. This ground signal is not tied to the NI ELVIS GROUND signals.
CH <ab>+</ab>	Oscilloscope	Oscilloscope Channels A and B (+)—Positive input for the Oscilloscope channels.
CH <ab>-</ab>	Oscilloscope	Oscilloscope Channels A and B (–)—Negative input for the Oscilloscope channels.
TRIGGER	Oscilloscope	Oscilloscope Trigger—Trigger input for the Oscilloscope, referenced to AIGND.
PFI <12>, PFI <57>	Programmable Function I/O	Programmable Function Input (PFI) 1 through 2 and 5 through 7—Programmable function I/O of the DAQ device. For more information about the PFI lines, refer to the DAQ device user manual.
SCANCLK	Programmable Function I/O	Scan Clock—Connected to the SCANCLK pin of the DAQ device. For more information about the SCANCLK signal, refer to the DAQ device user manual.
RESERVED	Programmable Function I/O	Connected to the EXTSTROBE* pin of the DAQ device. For more information about the EXTSTROBE* signal, refer to the DAQ device user manual.
3-WIRE	DMM	Three Wire—Voltage source for the DMM for three-wire transistor measurements.
CURRENT HI	DMM	Positive Current—Positive input for the DMM for all measurements besides voltage.
CURRENT LO	DMM	Negative Current—Negative input for the DMM for all measurements besides voltage.
VOLTAGE HI	DMM	Positive Voltage—Positive input for the DMM voltmeter.

 Table 3-1.
 Signal Descriptions (Continued)

Signal Name	Туре	Description
VOLTAGE LO	DMM	Negative Voltage—Negative input for the DMM voltmeter.
DAC<01>	General AO	Analog Channel Output for Channels 0 through 1—Outputs of the DAQ device D/A converters (DACs). For more information about the DAQ device analog output signals, refer to the DAQ device user manual.
FUNC_OUT	Function Generator	Function Output—Output of the Function Generator.
SYNC_OUT	Function Generator	Synchronization Output—TTL signal of the same frequency as the output as the FUNC OUT pin.
AM_IN	Function Generator	Amplitude Modulation Input—Input to the amplitude modulator for the Function Generator.
FM_IN	Function Generator	Frequency Modulation Input—Input to the frequency modulator for the Function Generator.
BANANA <ad></ad>	User Configurable I/O	Banana Jacks A through D—Connects to the banana jacks pins.
BNC <12>+	User Configurable I/O	BNC Connectors 1 and 2 (+)—Connects to the BNC pins.
BNC <12>-	User Configurable I/O	BNC Connectors 1 and 2 (–)—Connects to the BNC pins.
SUPPLY+	Variable Power Supplies	Positive—Output of 0 to 12 V variable power supply.
SUPPLY-	Variable Power Supplies	Negative—Output of –12 to 0 V variable power supply.
GROUND	Variable Power Supplies, DC Power Supplies	Ground—Prototyping board ground. These two ground signals are tied together.
+15 V	DC Power Supplies	+15 V Source—Output of fixed +15 V power supply, referenced to the NI ELVIS GROUND signal.
-15 V	DC Power Supplies	-15 V Source—Output of fixed -15 V power supply, referenced to the NI ELVIS GROUND signal.
+5V	DC Power Supplies	+5V Source—Output of fixed +5 V power supply, referenced to the NI ELVIS GROUND signal.
DO <07>	DIO	Digital Output Lines 0 through 7—Output of the write bus.
WR ENABLE	DIO	Write Enable—Output indicating data is being written to the write bus.
LATCH	DIO	Latch—Output that pulses after data is ready on the write bus.
GLB RESET	DIO	Global Reset—Output indicating global digital reset.
RD ENABLE	DIO	Read Enable—Output indicating data is being read from read bus.
DI <07>	DIO	Digital Input Lines 0 through 7—Output of read bus.
ADDRESS <03>	DIO	Address Lines 0 through 3—Output of address bus.

Signal Name Type Description CTR0 SOURCE Counters Counter 0 Source—Connected to the GPCTR0 SOURCE pin on the DAQ device. For more information about the GPCTR0_SOURCE signal, refer to the DAQ device user manual. CTR0 GATE Counters Counter 0 Gate—Connected to the GPCTR0_GATE pin on the DAQ device. For more information about the GPCTR0_GATE signal, refer to the DAQ device user manual. CTR0 OUT Counters Counter 0 Output—Connected to the GPCTR0_OUT pin on the DAQ device. For more information about the GPCTR0_OUT signal, refer to the DAQ device user manual. CTR1_GATE Counters Counter 1 Gate—Connected to the GPCTR1_GATE pin on the DAQ device. For more information about the GPCTR1_GATE signal, refer to the DAO device user manual. CTR1_OUT Counters Counter 1 Output—Connected to the GPCTR1_OUT pin on the DAQ device. For more information about the GPCTR1 OUT signal, refer to the DAQ device user manual. FREO OUT Counters Frequency Output—Connected to the FREQ_OUT pin on the DAQ device. For more information about the FREQ_OUT signal, refer to the DAQ device user manual. LED < 0..7> User Configurable I/O LEDs 0 through 7—Input to the LEDs.

Table 3-1. Signal Descriptions (Continued)

Grounding Considerations

User Configurable I/O

User Configurable I/O

DSUB SHIELD

DSUB PIN <1..9>

Because the analog channels are differential, you must establish a ground point somewhere in the signal path. As long as the signal you are measuring is referenced to one of the NI ELVIS GROUND pins, the measurement is correctly referenced. If a floating source, such as a battery, is being measured, be sure to connect one end of the signal to the NI ELVIS GROUND. Terminals for the NI ELVIS GROUND signal are located at several locations on the prototyping board. All these signals are tied together.

D-Sub Shield—Connection to D-Sub shield.

D-Sub Pins 1 through 9—Connection to D-Sub pins.

Connecting Analog Input Signals

This section describes how to connect AI signals on the NI ELVIS Prototyping Board. Refer to the DAQ device user manual for more information about types of signal sources, input modes, grounding configurations, and floating signal sources.

Generic Analog Input

The NI ELVIS Prototyping Board has six differential AI channels available—ACH<0..5>. These inputs are directly connected to the DAQ device input channels. The NI ELVIS also has two ground pins, AISENSE and AIGND, which are connected to the DAQ device ground pins. Table 3-2 shows how the NI ELVIS input channels map to the DAQ device input channels.

Table 3-2. Analog Input Signal Mapping

NI ELVIS Input Channel	DAQ Device Input Channel
ACH0+	ACH0
ACH0-	ACH8
ACH1+	ACH1
ACH1-	ACH9
ACH2+	ACH2
ACH2-	ACH10
ACH3+	ACH3
АСН3-	ACH11
ACH4+	ACH4
ACH4–	ACH12
ACH5+	ACH5
ACH5-	ACH13
AISENSE	AISENSE
AIGND	AIGND

The following sections describe some special considerations for connecting the AI signals on the prototyping board, including sections that specifically pertain to the Oscilloscope and DMM.

Resource Conflicts

Some of the AI channels are used by the internal circuitry for other instruments, but the majority of the time the channel can still be used. ACH<0..2> can be used without interruption. ACH5 is interrupted if any of the impedance-analyzing capabilities of the DMM, such as the capacitance meter, diode tester, and so on, are used. If you are using the Oscilloscope, disconnect any signals from ACH3 and ACH4 to avoid double driving the channels.



Caution By connecting different signals to both the DMM terminals on the prototyping board and the DMM connectors on the control panel, you are shorting them together, potentially damaging the circuit on the prototyping board.

DMM

Both the CURRENT and VOLTAGE inputs are available on the prototyping board along with an additional terminal for three-wire transistor measurements. The differential voltmeter inputs are labeled VOLTAGE HI and VOLTAGE LO. The rest of the functionality of the DMM is available through the CURRENT HI and CURRENT LO pins. The 3-WIRE pin is used for three-terminal device measurements in conjunction with the CURRENT HI and CURRENT LO pins.



Caution By connecting different signals to the Scope terminals on the prototyping board and the Scope connectors on the control panel, you are shorting them together, potentially damaging the circuit on the prototyping board.

Oscilloscope

The inputs of the Oscilloscope are available on the prototyping board as CH <A..B>+, CH <A..B>-, and TRIGGER. CH <A..B> are directly connected to ACH3 and ACH4, respectively, on the DAQ device. Refer to the *Generic Analog Input* section for more information about resource conflicts and grounding.

Connecting Analog Output Signals

This section describes how to connect the AO signals on the prototyping board.

Generic Analog Output

The NI ELVIS provides access to the two DAQ device DACs at the DAC0 and DAC1 terminals. These channels are used by the NI ELVIS hardware for arbitrary waveform generation.



Caution Other functions of the NI ELVIS, such as the DMM and FGEN, internally use these DACs and can potentially interfere with the measurements. The driver software generates an error message when there is a potential resource conflict.

DC Power Supplies

The DC power supplies output a static ±15 V and +5 V. For more information on the DC power supplies output, refer to Appendix A, *Specifications*.

Function Generator (FGEN)

Access to the Function Generator on the prototyping board has several additional terminals besides the function generator output signal, FUNC_OUT. The SYNC_OUT signal outputs a TTL-compatible clock signal of the same frequency as the output waveform. The AM_IN and FM_IN signals control the amplitude modulation (AM) and the frequency modulation (FM), respectively. These signals are in addition to the fine frequency and amplitude controls on the benchtop workstation. Software AM is controlled by DAC0 and software FM is controlled by DAC1.

Variable Power Supplies

The Variable Power Supplies provide adjustable output voltages from 0 to +12 V on the SUPPLY+ terminal and -12 to 0 V on the SUPPLY- terminal. The GROUND pin provides a connection to the same ground of the DC power supplies.

Connecting Digital I/O Signals

This section describes how to connect the DIO signals on the prototyping board.

The DIO circuitry of the NI ELVIS consists of an 8-bit read and write bus, four control signals and a 4-bit address bus.

The DO <0..7> signals are the digital outputs of digital circuitry. The DI <0..7> signals are the inputs to the digital circuitry. The four control lines, WR_ENABLE, LATCH, GLB_RESET, and RD_ENABLE are all active-low signals. While data is being written to the write bus, WR_ENABLE goes low. While data is being read from the read bus, RD_ENABLE goes low. When data is ready on the write bus, LATCH pulses. GLB_RESET is connected to the internal reset line, so the NI ELVIS internal circuitry can reset the digital circuitry built on the prototyping board.

Connecting Counter/Timer Signals

The prototyping board provides access to the DAQ device counter/timer inputs, which are also accessible from software. These inputs are used for counting TTL signals and for edge detection. The CTR0_SOURCE, CTR0_GATE, CTR0_OUT, CTR1_GATE, and CTR1_OUT signals are equivalent to the DAQ device GPCTR0_SOURCE, GPCTR0_GATE, GPCTR0_OUT, GPCTR1_GATE, and GPCTR1_OUT pins, respectively. Refer to the DAQ device user manual for details on counter/timer use and configuration.

The FREQ OUT signal is equivalent to the DAQ device FREQ_OUT signal. Refer to the DAQ device user manual for more information about this signal.

Connecting User-Configurable Signals

The prototyping board provides several different user-configurable connectors: four banana jacks, two BNC connectors, and a D-Sub connector. Each pin of the connector has a connection to the distribution strips of the prototyping board.

Eight LEDs are provided for general digital output. The anode of each LED is connected to the distribution strip through a 220 Ω resistor, and each cathode is connected to ground.

Refer to Table 3-1 for more information about the signal names for the user-configurable I/O connectors.

Programming NI ELVIS

An NI ELVIS measurement system is composed of the NI ELVIS hardware, the DAQ device, and the LabVIEW software that controls the hardware. Various measurements can be performed by NI ELVIS using either the NI-DAQ driver or the NI ELVIS instrument driver. Three standard measurement functions of DAQ devices—AI, AO, and TIO—can be utilized when connected to the NI ELVIS Benchtop Workstation. The fourth DAQ device function, DIO, is unavailable with an NI ELVIS measurement system since the DAQ device DIO communicates with the control circuitry of the benchtop workstation. Additionally, the NI ELVIS Benchtop Workstation has Variable Power Supplies, a Function Generator, a DMM, and DIO that you can control using the NI ELVIS instrument driver, which is located in the functions palette under Instrument I/O» Instrument Drivers»NI ELVIS.

This chapter explains how to program the NI ELVIS hardware using NI-DAQ and the NI ELVIS Instrument Driver. This chapter is not intended to be an exhaustive guide to programming with LabVIEW or NI-DAQ; its purpose is instead to familiarize you with concepts you should know about when programming NI ELVIS.

For more information on programming with NI-DAQ or LabVIEW, refer to the NI-DAQ documentation that shipped with the device or to the *LabVIEW Measurements Manual*.

Programming NI ELVIS Using NI-DAQ

This section explains how to program NI ELVIS for AI, AO, and timing and control I/O applications. You can find other examples for using NI ELVIS for AI, AO, and counter/timer applications by launching LabVIEW and selecting **Find Examples»Hardware Input and Output» DAQ** and then the type of example, or you can find examples by selecting **Find Examples** and then searching for NI ELVIS.



Note The DIO examples within LabVIEW do not work with the DIO lines of the NI ELVIS hardware. Refer to the *Using the DAQ Hardware in Bypass Mode* section of

Chapter 3, *Hardware Overview*, for more information about using the communications bypass.

Analog Input

You can use NI ELVIS to measure up to six differential AI channels: ACH<0..5>.



Note The DAQ device must be configured for differential AI mode before making connections to the NI ELVIS Benchtop Workstation. For information on configuring the DAQ device, refer to the *Measurement & Automation Explorer Help for DAQ*, which you can access by launching MAX, then selecting **Help*Help Topics*NI-DAQ**.

ACH<0..5> on the NI ELVIS Prototyping Board directly connect to corresponding AI channels on the DAQ device. ACH<0..5> can be used as normal input channels for any existing DAQ examples or for when you program with the LabVIEW Data Acquisition VIs. ACH5 is also used for measurements by the following NI ELVIS software instruments: Oscilloscope, DMM, DSA, Impedance Analyzer, Two-Wire Current-Voltage Analyzer, and Three-Wire Current-Voltage Analyzer. ACH5 might be unavailable if these software instruments are running.

Refer to the *NI ELVIS Prototyping Board* section of Chapter 3, *Hardware Overview*, for an illustration of signal connections on the prototyping board.

Typical AI measurements include buffered continuous acquisitions and finite acquisitions with a start trigger. For more information on how to perform an AI acquisition using NI-DAQ, refer to the NI-DAQ documentation that shipped with the DAQ device.



Caution ACH3 and ACH4 are used for Oscilloscope measurements on CH A and CH B, respectively. Do not connect signals to these channels on the prototyping board and the front panel BNC **Scope** connectors at the same time.

Analog Output

NI ELVIS allows access to the two analog outputs of a DAQ device through connectors on the prototyping board. The AO signals labeled DAC0 and DAC1 connect to the signals of the same name on the DAQ device. These signals can be used as normal output channels for any existing DAQ examples and for when you program with DAQ VIs.

Refer to the *NI ELVIS Prototyping Board* section of Chapter 3, *Hardware Overview*, for an illustration of signal locations on the prototyping board.

The output channels are also used by the following NI ELVIS SFP instruments: FGEN, DMM, Impedance Analyzer, Two-Wire Current-Voltage Analyzer, and Three-Wire Current-Voltage Analyzer. The output channels may not be available if these SFP instruments are running.

Typical AO applications include continuous waveform generation and single-point output updates. For more information on how to perform AO generation using NI-DAQ, refer to the NI-DAQ documentation that shipped with the DAQ device.

Timing and Control I/O

NI ELVIS provides access to the two counter/timers of the DAQ device. Table 4-1 shows how NI ELVIS counter signals correlate with DAQ device timing signals.

NI ELVIS	DAQ Device
CTR<01>_SOURCE	GPCTR<01>_SOURCE
CTR<01>_GATE	GPCTR<01>_GATE
CTR<01>_OUT	GPCTR<01>_OUT

Table 4-1. Counter Signal Correlations

CTR0 and CTR1 can be used as normal counter/timers for any existing DAQ examples and for when you program with DAQ VIs. The counter/timers are also used by the NI ELVIS software Function Generator instrument. The counter/timers might be unavailable if the soft front panel Function Generator instrument is running.

Refer to the *NI ELVIS Prototyping Board* section of Chapter 3, *Hardware Overview*, for an illustration of signal connections on the prototyping board.

Typical counter/timer applications include pulse train generation, event counting, and frequency measurement. For more information on how to perform counter/timer measurements using NI-DAQ, refer to the NI-DAQ documentation that shipped with the DAQ device.

NI ELVIS also provides access to the programmable function input (PFI) pins on the DAQ device. These pins are typically used in advanced applications that require external control of a measurement. Examples of these advanced applications include triggering and scan clock control.

For more information on the PFI pins, refer to the DAQ device user manual. For more information on how to use the PFI pins using NI-DAQ, refer to the NI-DAQ documentation that shipped with the DAQ device.

Programming NI ELVIS Using the NI ELVIS LabVIEW API

An instrument driver is a set of software routines that control a programmable instrument. Each routine corresponds to a programmatic operation such as configuring, reading from, writing to, and triggering the instrument. Instrument drivers simplify instrument control by eliminating the need to learn the programming protocol for the instrument.

The NI ELVIS instrument driver is a collection of LabVIEW VIs that provides an API for controlling the NI ELVIS hardware. The API allows the user to connect VIs in a logical manner to control the instruments of the NI ELVIS Benchtop Workstation—the Variable Power Supplies, Function Generator, DMM, and DIO.

The general programming flow when using the NI ELVIS instrument driver is Initialization - Action - Close. The initialization VIs establish communication with the NI ELVIS Benchtop Workstation and configure the selected components to a defined state. A reference (refnum) to the specific component is generated and then used by subsequent VIs to perform the desired actions.

The instrument driver handles the resource sharing that occurs between the components of the NI ELVIS. For example, the DMM uses the Function Generator for its measurements. Without resource management, if an application using the Function Generator is running, when a DMM application runs, one or both applications might return incorrect results. To prevent this problem, if the driver detects that a resource is in use, an error is returned. Resource management is valid within one LabVIEW process only. Therefore, if an application (executable) built using the NI ELVIS instrument driver is running at the same time as another application using the driver (LabVIEW development environment), resource management is not in affect across the processes, and incorrect behavior can occur.

The *NI ELVIS Online Help* includes function reference topics for each instrument API that lists and describes parameters for each instrument VI.



Note To ensure correct behavior with programs that use NI ELVIS with the instrument driver, first you must close the SFP instruments.

You can find other examples for using NI ELVIS for AI, AO, and counter/timer applications by launching LabVIEW and selecting **Find Examples»Hardware Input and Output»DAQ** and then the type of example, or you can find examples by selecting **Find Examples** and then searching for NI ELVIS.

Variable Power Supplies

The NI ELVIS Benchtop Workstation has two variable power supplies that can be controlled using the NI ELVIS instrument driver. The driver allows the user to select which supply to control and to set its output voltage. A simple variable power supply application is shown in Figure 4-1.

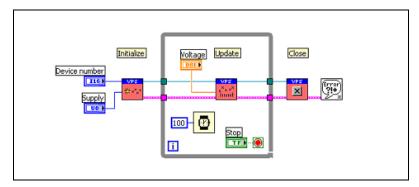


Figure 4-1. Simple Variable Power Supply Application

The supply to control is selected during initialization and then updated continuously in the loop. When the loop ends, the supply reference is closed and the output is set to zero. The DAQ device number is provided to identify the DAQ device that is cabled to the NI ELVIS Benchtop Workstation.

Refer to the *NI ELVIS Online Help* for more information about the specific VIs in the variable power supply API.

Function Generator

The NI ELVIS Benchtop Workstation has a function generator that can be controlled using the NI ELVIS instrument driver. The driver allows the user to update the frequency, peak amplitude, DC offset, and type of the waveform that the function generator outputs. A simple application is shown in Figure 4-2.

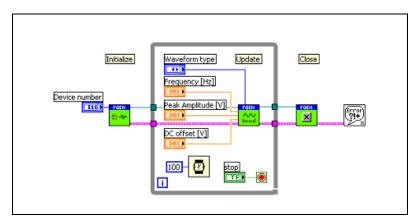


Figure 4-2. Simple Function Generator Application

The output of the function generator is set to zero during initialization and then the waveform parameters are continuously updated in the loop. When the loop ends, the function generator reference is closed and the output is set to zero. The DAQ device number is provided to identify the DAQ device that is cabled to the NI ELVIS Benchtop Workstation.

The advanced features of the Function Generator—the Tuning and AO Modulation controls—can be configured using the FGEN-Configure VI. By default, both these features are disabled. The refnum that is passed between the API VIs contains information about the current configuration state. If the configuration VI is used in a loop, you should wire the refnum to shift registers so that the refnum information persists between loops.

Refer to the *NI ELVIS Online Help* for more information about the specific VIs in the function generator API.

Digital Multimeter

The NI ELVIS Benchtop Workstation contains circuitry that combines with the DAQ hardware to allow DMM-type measurements such as voltage, current, and resistance. The DMM hardware can be controlled using the NI ELVIS instrument driver. The driver allows the user to configure the measurement type and read the measurement results. A simple application is shown in Figure 4-3.

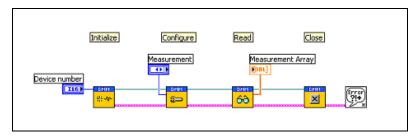


Figure 4-3. Simple DMM Application

The type of measurement is configured, the measurement value is returned, and then the DMM reference is closed. The DAQ device number is provided to identify the DAQ device that is cabled to the NI ELVIS Benchtop Workstation. Refer to the DAQ documentation that shipped with the DAQ device for more information about device numbers.

The refnum that is passed between the API VIs contains information about the current configuration state. If the configuration VI is used in a loop, you should wire the refnum to shift registers so that the refnum information persists between loops.

Refer to the *NI ELVIS Online Help* for more information about the specific VIs in the DMM API.

Digital I/O

The DAQ device digital lines are used to control the NI ELVIS Benchtop Workstation. Therefore, those lines are not directly accessible on the prototyping board. However, the benchtop workstation contains circuitry that multiplexes the DAQ DIO lines to provide digital input and output signals. The DIO hardware can be controlled using the NI ELVIS instrument driver. The driver allows the user to configure the digital operation and read or write 8-bit digital data. A simple application to perform digital input is shown in Figure 4-4.

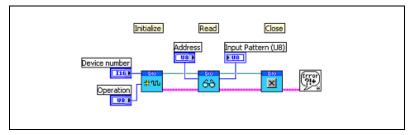


Figure 4-4. Simple Digital I/O Input Application

The digital operation is configured, the digital data is returned, and then the DIO reference is closed

A simple application to perform digital output is shown in Figure 4-5.

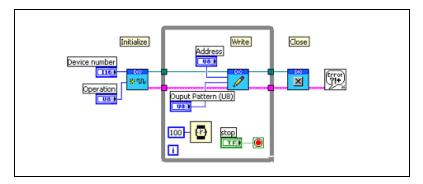


Figure 4-5. Simple Digital I/O Output Application

The digital operation is configured, the digital data is output, and then the DIO reference is closed. The DAQ device number is provided to identify the DAQ device that is cabled to the NI ELVIS Benchtop Workstation.

Refer to the *NI ELVIS Online Help* for more information about the specific VIs in the DIO API.

Scope

The Oscilloscope component of NI ELVIS is not addressed in the instrument driver since you can use NI-DAQ to directly access its functionality.



Specifications

This appendix lists the specifications of the NI ELVIS. These specifications are typical after a 30 minute warm-up time, at 25 $^{\circ}$ C, unless otherwise noted.

Analog Input

Refer to the *Analog Input* section of the *Specifications* of the DAQ device user manual.

Arbitrary Waveform Generator¹

Number of output channels	. 2
Maximum frequency	. DC to DAQ device AO update rate/10
Full-power bandwidth	27 kHz
Output amplitude	±10 V
Resolution	. 12 bits or 16 bits, DAQ device dependent
Output drive current	25 mA
Output impedance	1 Ω
Slew rate	1.5 V/μs

Bode Analyzer

Amplitude accuracy	12 or 16 bits,
	DAQ device dependent
Phase accuracy	1 degree
Frequency range	5 Hz–35 kHz

¹ The Arbitrary Waveform Generator does not work with the NI 6014 or NI 6024.

Digital I/O

DC Power Supplies

+15 V Supply

TIO V Oupply	
Output currentFused at 500	mA
Output voltage	max
Line regulation	
Ripple and noise1%	
-15 V Supply	
Output current	mA ¹
Output voltage15 V at ±5%	max
Line regulation	
Ripple and noise1%	
+5 V Supply	
Output currentFused at 2 A	
Output voltage+5 V at ±5%	max
Line regulation	
Ripple and noise1%	
Digital input resolution8 bits	
Digital output resolution8 bits	
Digital addressing4 bits	

 $^{^{1}}$ Total current drawn from -15~V supply and variable power supplies cannot exceed 500~mA.

Capacitance Measurement

Continuity Measurement

Current Measurement

Accuracy

Range±250 mA in two ranges, max

Voltage burden 2 mV/mA

Diode Measurement³

Voltage threshold 1.1 V max

¹ 25 Hz to 10 kHz

² Proper null correction at the common-mode voltage can reduce the ±3 mA offset error to 200 µA of noise.

³ The Two-Wire Current Voltage Analyzer SFP is the recommended instrument for diode measurement.

Inductance Measurement

Accuracy	1%
Range	100 µH–100 mH
Test frequency	950 Hz, software-selectable
Test frequency voltage	1 V _{p-p} sine wave, software-selectable

Resistance Measurement

Accuracy	1%
Range	5 Ω –3 M Ω , in four ranges
Test frequency	120 Hz, software-selectable
Test frequency voltage	1 V _{p-p} sine wave, software-selectable

Voltage Measurement

Α.	-	7
A	l	

Accuracy	$0.3\% \pm .001\%$ full-scale ¹
Range	±14 V _{rms} in four ranges, max

DC

Accuracy	0.3% \pm .001% full-scale, max
Range	±20 V in four ranges, max
Input impedance	1 MΩ

Dynamic Signal Analyzer

Input range	±10 V in four ranges
Input resolution	12 bits or 16 bits,
	DAQ device dependant

Function Generator

Frequency range

-

¹ 100 Hz to 10 kHz

Impedance Analyzer

Measurement frequency range 5 Hz-35 kHz

Oscilloscope

Refer to the *Analog Input* section of Appendix A, *Specifications*, in the DAQ device user manual.

	Maximum input bandwidth	10 kHz–50 kHz, DAQ device dependent
	Vertical resolution	12 bits or 16 bits, DAQ device dependent
Two-Wire Cur	rent-Voltage Analyzer	
	Current range	±10 mA
	Voltage sweep range	±10 V
Three-Wire Co	urrent-Voltage Analyzer¹	
	Minimum base current increment	15 μΑ
	Maximum collector current	10 mA
	Maximum collector voltage	10 V
Variable Powe	er Supplies	
	Positive Supply	
	Output voltage	12 V
	Ripple and noise	0.25%
	Software-controlled resolution	7 bits
	Current limiting	0.5 V at 160 mA, 5 V at 275 mA, 12 V at 450 mA
	Negative Supply	
	Output voltage	12 V
	Ripple and noise	0.25%
	Software-controlled resolution	7 bits
	Current limiting	0.5 V at 130 m A 5 V at 290m A

12 V at 450mA²

ni.com

NI ELVIS User Manual A-6

¹ This SFP instrument is intended for use only with NPN BJT transistors.

 $^{^{2}\,}$ Total current drawn from –15 V and the negative variable power supply cannot exceed 500 mA.

Maximum Working Voltage

Maximum working voltage refers to the signal voltage plus the common-mode voltage.

Channel-to-earth.....±20 V, Installation Category I

Channel-to-channel±20 V, Installation Category I

Environmental

Operating temperature...... 0 to 40 °C

Storage temperature-20 to 70 °C

Pollution Degree (indoor use only)...... 1

Safety

This product is designed to meet the requirements of the following standards of safety for electrical equipment for measurement, control and laboratory use:

IEC 61010-1, EN 61010-1

UL 3111-1, UL 61010B-1

CAN/CSA C22.2 No. 1010.1



Note For UL and other safety certifications, refer to the product label or to ni.com.

Electromagnetic Compatibility

Emissions: EN 55011 Class A at 10 m. FCC Part 15A above 1 GHz

Immunity: EN 61326:1997 + A2:2001, Table 1

CE, C-Tick and FCC Part 15 (Class A) Compliant



Note For full EMC compliance, you *must* operate this device with shielded cabling. In addition, all covers and filler panels must be installed.

CE Compliance

This product meets the essential requirements of applicable European Directives, as amended for CE marking, as follows:

Low-Voltage Directive (safety)......73/23/EEC

Electromagnetic Compatibility
Directive (EMC)89/336/EEC



Note Refer to the Declaration of Conformity (DoC) for this product for any additional regulatory compliance information. To obtain the DoC for this product, click **Declarations** of Conformity Information at ni.com/hardref.nsf/.

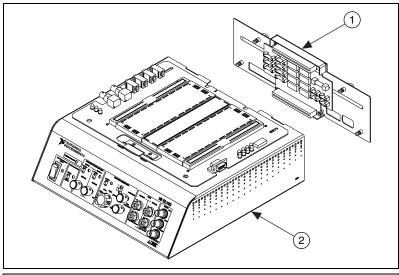


Protection Board Fuses

This appendix describes the fuses on the NI ELVIS Protection Board and gives instructions on how to remove the protection board from the NI ELVIS Benchtop Workstation, debug the protection board, and change fuses.

Removing the Protection Board

The Protection Board detaches from the NI ELVIS Benchtop Workstation as shown in Figure B-1. Refer to *Where to Start with the NI ELVIS* for more parts locator diagrams of the NI ELVIS Benchtop Workstation.



1 NI ELVIS Protection Board

2 NI ELVIS Benchtop Workstation

Figure B-1. NI ELVIS Benchtop Workstation with Protection Board Removed

Complete the following steps to remove the protection board from the benchtop workstation. Refer to Figure B-1 as needed.

- 1. Move the NI ELVIS Power Switch to **Standby**. The **Standby** switch is located on the back side of the benchtop workstation. Refer to *Where to Start with the NI ELVIS* for an illustration of the switch location.
- 2. Unplug the 68-pin cable and the power supply cable from the benchtop workstation
- 3. Disconnect the prototyping board from the benchtop workstation.
- Unscrew the captive screws located on the back of the NI ELVIS Protection Board.
- 5. Gently pull on the captive screws to remove the protection board.

Debugging the Protection Board

The protection board provides a level of electrical protection between the prototyping board and the motherboard of the NI ELVIS. This protection consists of fuses for the high-current signals—such as the power supplies, AO channels, and DMM—and 100 Ω current-limited resistors for the low-current signals, such as the AI channels, and digital signals. If too much current begins to flow to or from a particular signal on the prototyping board, the fuse or resistor breaks down, opening the connection electrically.

To debug the protection board, you need a DMM with an ohmmeter. Complete the following steps:

- 1. Verify that the NI ELVIS is in Standby mode. The **Standby** switch is located on the back of the NI ELVIS benchtop workstation.
- 2. Remove the protection board assembly from the rest of the NI ELVIS workstation. For instructions on removing the protection board, refer to the *Removing the Protection Board* section.
- 3. Check the fuses, since these signals are much more likely to have been overloaded. To check the fuse, verify that the resistance across the fuse is less than 50 Ω . If all the fuses are operational, proceed to the resistor packs.
- 4. Verify that the resistance across each resistor is 100Ω , $\pm 5\%$. One resistor is located between each of the following pairs of pins: 1 and 16, 2 and 15, 3 and 14, 4 and 13, 5 and 12, 6 and 11, 7 and 10, and 8 and 9. The resistor packs are socketed so that you can easily replace resistors.



Caution Before restoring power to the circuit, be sure the problem that caused the protection board component to fail has been resolved to keep the same fuse or resistor from failing again.

If you need to replace a fuse, use the fuse types listed in Table B-1.



Caution For continued protection against fire, replace only with fuses of the same type and rating. Refer to the Table B-1 for fuse types.

Table B-1. NI ELVIS Fuse Information

Fuse Rating	Fuse Type	Manufacturer
0.5 A/250 V	5 × 20 mm, Slow acting	LittelFuse
0.5 A/250 V	2AG, Fast acting	LittelFuse
2 A/250 V	3AG, Fast acting	LittelFuse



Caution The fuses on the NI ELVIS are glass. Use care when removing the fuses to prevent injury from broken glass.

Figure B-2 shows the location of the different fuses for the NI ELVIS hardware and the location of the resistor packs.

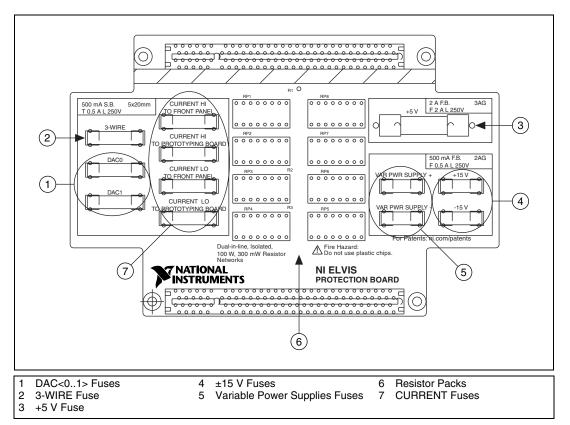


Figure B-2. Parts Locator Diagram for NI ELVIS Protection Board

Reinstalling the Protection Board

Reinstall the NI ELVIS Protection Board before resuming use of the NI ELVIS. To replace the protection board, complete the following steps:

- 1. Reinsert the PCI connector of the protection board into the benchtop workstation rear connector.
- 2. Tighten the four captive screws located on the back of the protection board.
- 3. Plug in the 68-pin cable and the power supply.
- 4. Power on the NI ELVIS.



Technical Support and Professional Services

Visit the following sections of the National Instruments Web site at ni.com for technical support and professional services:

- **Support**—Online technical support resources include the following:
 - Self-Help Resources—For immediate answers and solutions, visit our extensive library of technical support resources available in English, Japanese, and Spanish at ni.com/support. These resources are available for most products at no cost to registered users and include software drivers and updates, a KnowledgeBase, product manuals, step-by-step troubleshooting wizards, conformity documentation, example code, tutorials and application notes, instrument drivers, discussion forums, a measurement glossary, and so on.
 - Assisted Support Options—Contact NI engineers and other measurement and automation professionals by visiting ni.com/support. Our online system helps you define your question and connects you to the experts by phone, discussion forum, or email.
- Training—Visit ni.com/custed for self-paced tutorials, videos, and interactive CDs. You also can register for instructor-led, hands-on courses at locations around the world.
- **System Integration**—If you have time constraints, limited in-house technical resources, or other project challenges, NI Alliance Program members can help. To learn more, call your local NI office or visit ni.com/alliance.

- Declaration of Conformity (DoC)—A DoC is our claim of compliance with the Council of the European Communities using the manufacturer's declaration of conformity. This system affords the user protection for electronic compatibility (EMC) and product safety. You can obtain the DoC for your product by visiting ni.com/hardref.nsf.
- Calibration Certificate—If your product supports calibration, you can obtain the calibration certificate for your product at ni.com/calibration.

If you searched ni.com and could not find the answers you need, contact your local office or NI corporate headquarters. Phone numbers for our worldwide offices are listed at the front of this manual. You also can visit the Worldwide Offices section of ni.com/niglobal to access the branch office Web sites, which provide up-to-date contact information, support phone numbers, email addresses, and current events.

Glossary

Symbol	Prefix	Value
p	pico	10-12
n	nano	10-9
μ	micro	10-6
m	milli	10-3
k	kilo	103
M	mega	106

Symbols

% percent

negative of, or minus

positive of, or plus

/ per

degree

 $\Omega \hspace{1cm} \text{ohm}$

± plus or minus

A

A amperes

AC alternating current

ACH analog input channel signal

ADDRESS the DIO output signals of the address bus

AI analog input

AIGND analog input ground signal

AISENSE analog input sense signal

AM amplitude modulation—the process in which the amplitude of a carrier

wave is varied to be directly proportional to the amplitude of the

modulating signal

AM IN amplification modulation input signal

amplification a type of signal conditioning that improves accuracy in the resulting

digitized signal and reduces noise

amplitude the voltage amplitude of a signal. When speaking of the amplitude of a

signal, it is usually assumed to be the RMS value for an AC signal. However, amplitude can also refer to the instantaneous amplitude, or the

peak, peak-to-peak, or average amplitude, if so specified.

AO analog output

ARB arbitrary waveform generator

В

block diagram pictorial description or representation of a program or algorithm. The block

diagram, consists of executable icons called nodes and wires that carry data between the nodes. The block diagram is the source code for the VI. The

block diagram resides in the block diagram window of the VI.

BNC a type of coaxial signal connector

board refers to the DAO device

bode plot the plot of the gain and phase of a system as a function of frequency

bus the group of conductors that interconnect individual circuitry in a computer.

Typically, a bus is the expansion vehicle to which I/O or other devices are

connected. An example of a PC bus is the PCI bus.

C

C Celsius

capacitance the ability to hold an electrical charge

CH channel

channel pin or wire lead to which you apply or from which you read the analog or

digital signal. Analog signals can be single-ended or differential. For digital signals, you group channels to form ports. Ports usually consist of either

four or eight digital channels.

counter/timer a circuit that counts external pulses or clock pulses (timing)

CTR0_GATE counter 0 gate signal

CTR0_OUT counter 0 output signal

CTR0_SOURCE counter 0 source signal

CTR1_GATE counter 1 gate signal

CTR1_OUT counter 1 output signal

CURRENT input signals for current-related measurements for the DMM

D

D/A digital-to-analog

DAC D/A converter

DAQ data acquisition

dB decibel—the unit for expressing a logarithmic measure of the ratio of two

signal levels: $dB = 20\log 10 \text{ V}1/\text{V}2$, for signals in volts

DC direct current

default setting a default parameter value recorded in the driver. In many cases, the default

input of a control is a certain value (often 0) that means use the current

default setting.

DI digital I/O input signals sent to the DI bus

differential input an analog input consisting of two terminals, both of which are isolated from

computer ground, whose difference is measured

digital trigger a TTL level signal having two discrete levels—a high and a low level

DIO digital I/O

diode a specialized electronic component with two electrodes called the *anode*

and the cathode

DMM digital multimeter

DO digital I/O output signals from the DO bus

DOC Canadian Department of Communications

DSA dynamic signal analyzer

E

ECG electrocardiogram

EEPROM electrically erasable programmable read-only memory—ROM that can be

erased with an electrical signal and reprogrammed

ELVIS Educational Laboratory Virtual Instrumentation Suite

EMC electromechanical compliance

EMI electromagnetic interference

EXTSTROBE external strobe signal

F

FCC Federal Communications Commission

FGEN function generator

floating signal sources signal sources with voltage signals that are not connected to an absolute

reference or system ground. Also called nonreferenced signal sources.

Some common example of floating signal sources are batteries,

transformers, or thermocouples.

FM_IN frequency modulation input signal

FREQ_OUT frequency output signal

frequency the basic unit of rate, measured in events or oscillations per second using a

frequency counter or spectrum analyzer. Frequency is the reciprocal of the

period of a signal.

front panel the user interface of a LabVIEW virtual instrument

FUNC_OUT output signal for the function generator

G

gain the factor by which a signal is amplified, sometimes expressed in decibels

GPCTR0_GATE general purpose counter timer 0 gate signal, available from a DAQ device

GPCTR0_OUT general purpose counter timer 0 output signal, available from a DAQ device

GPCTR0_SOURCE general purpose counter timer 0 clock source signal, available from a

DAQ device

GPCTR1_GATE general purpose counter timer 1 gate signal, available from a DAQ device

GPCTR1 OUT general purpose counter timer 1 output signal, available from a

DAQ device

GPCTR1 SOURCE general purpose counter timer 1 clock source signal, available from a

DAQ device

GROUND prototyping board ground signal

Н

hardware triggering a form of triggering where you set the start time of an acquisition and gather

data at a known position in time relative to a trigger signal

Hz hertz—the number of scans read or updates written per second

I

I/O input/output—the transfer of data to/from a computer system involving

communications channels, operator interface devices, and/or data

acquisition and control interfaces

in. inch or inches

inductance the characteristic of a coil that generates a voltage due to changes in the

current. An inductor creates a voltage that is the derivative of the current, while a capacitor creates a voltage that is the integral of the current.

L

LabVIEW a graphical programming language

LATCH DIO output signal that pulses when data is ready on the write bus

LED light-emitting diode

N

NI-DAQ National Instruments driver software for DAQ hardware

NRSE nonreferenced single ended mode—all measurements are made with

respect to a common (NRSE) measurement system reference, but the voltage at this reference can vary with respect to the measurement system

ground

0

op-amp operational amplifier—pre-built amplifier modules that are general enough

to be used almost anywhere an amplifier is needed

P

PCB printed circuit board

PCI Peripheral Component Interconnect—a high-performance expansion bus

architecture originally developed by Intel to replace ISA and EISA. It is achieving widespread acceptance as a standard for PCs and workstations;

it offers a theoretical maximum transfer rate of 132 Mbytes/s.

peak to peak a measure of signal amplitude; the difference between the highest and

lowest excursions of the signal

PFI programmable function input

potentiometer an electrical device the resistance of which can be manually adjusted; used

for manual adjustment of electrical circuits and as a transducer for linear or

rotary position

R

RD_ENABLE read enable signal—DIO output signal that indicates when data is being

read from the read bus

referenced signal

sources

signal sources with voltage signals that are referenced to a system ground, such as the earth or a building ground. Also called grounded signal sources.

resistance the resistance to the flow of electric current. One ohm (Ω) is the resistance

through which one volt of electric force causes one ampere to flow.

rms root mean square

S

s seconds

S samples

S/s samples per second—used to express the rate at which a DAQ device

samples an analog signal

SCANCLK scan clock signal

Scope abbreviation for oscilloscope

SYNC_OUT TTL signal of the same frequency of the function generator

T

TIO timing I/O

TRIG trigger signal

trigger any event that causes or starts some form of data capture

TRIGGER trigger input signal for the oscilloscope

TTL transistor-to-transistor logic

V

V volts

VI virtual instrument—a combination of hardware and/or software elements,

typically used with a PC, that has the functionality of a classic stand-alone

instrument.

VOLTAGE input signals for the DMM voltmeter

 $V_{\text{p-p}}$ peak-to-peak voltage

W

waveform multiple voltage readings taken at a specific sampling rate

WR_ENABLE DIO output signal that indicates data is being written to the write bus

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